

Conference on imaging on the nanometer scale across borders and disciplines

We invite researchers working in any fields of nanometer scale imaging to participate and share their latest techniques and scientific progress, and exchange ideas in a short, focused conference.

Examples of topics of interest include, but are not limited to scanning probe microscopy, electron microscopy, NV center imaging, X-ray imaging, or advanced optical imaging

Important dates:

14 January 2019 Registration and abstract submission opens07 April 2019 Final abstract submission and registration

14 May 2019 Notification of acceptance

Please find more information on: www.nanosciencefocus.unibas.ch



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